Se	arc	h l	No	tes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/694,797	SHIMIZU ET AL.
Examiner	Art Unit
Luan K. Bui	3728

SEARCHED				
Class	Subclass	Date	Examiner	
206	205	1/25/2006	LKB	
	213.1			
	524.8			
53	403, 405			
	408, 432			
347	2, 28	* "		
	86, 108			

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
TEXT	1/25/2005	LKB		
		e.		
	Subclass	Subclass Date		

(INCLUDING SEAR	CH STRATEGY	<u>()</u>
	DATE	EXMR

		<u> </u>
		<u> </u>